Form PTO-1449 (Modified)
PATENTS AND PUBLICATIONS
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ATTY. DOC T NO. 83175
APPLICANT

Tak Kin Chu et al. FILING DATE

May 9, 2001

SERIAL NO. 09/853,925

GROUP ART UNIT 2813

	REFE	RENCE DESIGN	ATION	U.S. PATENT DOC	UMENTS		
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DAT IF APPROPRIAT
EK	AA	5,690,737	11/25/97	Santiago et al.	117	92	
<u> </u>	AB	5,695,810	12/9/97	Dubin et al.	427	96	
	AC	5,824,599	10/20/98	Schacham-Diamand et al.	438	678	
	AD	5,225,031	7/6/93	McKee et al.	156	612	
	AE	5,248,633	9/28/93	Morar et al.	437	196	_
	AF	5,378,905	1/3/95	Nakamura	257	213	
	AG	5,482,003	1/9/96	McKee et al.	117	108	
	AH	5,569,538	10/29/96	Cho	428	427	RECEIVED JUL 18 2003
	AI	5,593,951	1/14/97	Himpsel	505	235	JUL REC
	AJ	5,637,533	6/10/97	Choi	438	643	CEI CEI
	AK	5,670,420	9/23/97	Choi	437	189	B 20 ENT
	AL	5,677,572	10/14/97	Hung et al.	257	750	
	AM	5,696,018	12/9/97	Summerfelt et al.	437	60	2800
	AN	5,753,040	5/19/98	Cho	117	106	
	AO	5,773,085	6/30/98	Inoue et al.	427	255.2	
	AP	5,824,590	10/20/98	New	438	393	
	AQ	4,291,327	9/22/81	Tsang	357	52	
	AR	4,550,331	10/29/85	Milano	357	24	
	AS	4,692,993	9/15/87	Clark et al.	437	53	
	AT.	4,847,666	7/11/89	Heremans et al.	357	16	
,	AU	4,915,746	4/10/90	Welsch	148	4	
	AV	5,124,762	6/23/92	Childs et al.	357	16	
1.	AW	5,151,168	9/29/92	Gilton et al.	205	123	
	AX	5,435,264	7/25/95	Santiago et al.	117	92	
1	AY	5,391,517	2/21/95	Gelatos et al.	437	190	
	AZ	5,773,359	6/30/98	Mitchell et al.	438	614	
Eic	BA	2001/0035581	11/1/01	Stumborg et al.	257	751	

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. =		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
T K	BB ;	851,483	7/1/98	EPO			Yes
ER	BC ♥	881,673	12/2/98	EPO			Yes
ER	BD 1	2-266569	10/31/90	Japan			Abstract only
ER	BE ?	6-310509	11/4/94	Japan			Yes

\mathbb{X}	PI	= 70		OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)				
q	5	6 7003	BF	• • • • • • • • • • • • • • • • • • • •				
H	W I	E ZUUS	BG	applications", Appl. Phys. lett., Vol. 62, No. 8, 22 Feb. 1993, pp. 852-854. Colbow et al., "Photoemission study of the formation of SrF ₂ /GaAs(100) and BaF ₂ /GaAs(100) interfaces",				
	4	1		Physical Review B, Vol. 49, No. 3, 15 Jan. 1994, pp. 1750-1756.				
Y	TENT :	TRADEM	ВН	Chu et al., "The Role of Barium in the Heteroepitaxial Growth of Insulator and Semiconductors on Silicon", Mat. Res. Soc. Symp. Proc., Vol. 334, 1994, pp. 501-506.				
			BI	Stumborg et al., "Determination of growth mechanisms of MBE grown BaF ₂ on Si(100) by target angle dependence of RBS yields", Nucl. Instr. And Methods in Physics Res. B, Vol. 95, 1995, pp. 319-322.				
			BJ	Stumborg et al., "Growth and interfacial chemistry of insulating (100) barium fluoride on gallium arsenid J. Appl. Phys., Vol. 77, No. 6, 15 March 1995, pp. 2739-2744.				
			вк	Stumborg et al., "Surface chemical state populations in the molecular beam epitaxy deposition of BaF ₂ on GaAs by x-ray photoelectron spectroscopy and heavy-ion backscattering spectroscopy", J. Vac. Sci, Technol., Vol. 14, No. 1, Jan./Feb. 1996, pp. 69-79.				
			BL	Chu et al., "Heteroepitaxial deposition of Group IIa fluorides on gallium arsenide", Mat. Sci. and Eng., Vol. B47, 1997, pp. 224-234.				
			BM	D. Gardner et al., "Encapsulated Copper Interconnection Devices using Sidewall Barriers", Proc. 8 th I IEEE VLSI MVIC, June 1991, pp. 99-108.				
			BN					
			во	Abe et al., "Metal Base Transistor of In/Bi (Ba,Rb)O ₃ /SrTiO ₃ (Nb)", IEEE, Vol. 14, March 1993, pp. 100-102.				
			BP	S. M. Sze, "Semiconductor Devices Physics and Technology", 1985, pp. 208-210.				
			BQ	Truscott et al., "MBE growth of BaF ₂ /(Ga,In)(As,Sb) Structures", Journal of Crystal Growth, Vol. 81 (1987), pp. 552-556.				
		/	BR	Clemens et al., "Growth of BaF ₂ and of BaF ₂ /SrF ₂ layers on (001) oriented GaAs", J.Appl. Phys., Vol. 66, No. 4, 15 Aug. 1989, pp. 1680-1685.				
	٤	R	BS	Hung et al., "Epitaxial growth of alkaline earth fluoride films on HF-treated Si and (NH ₄) ₂ S _x -treated GaAs without in situ cleaning", Appl. Phys. Lett., Vol. 60, No. 2, 13 Jan. 1992, pp. 201-203.				

EXAMINER DATE CONSIDERED

EXAMINER: Initial if reference considered whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

(Information Disclosure Statement - Section 9 PTO-1449 (Modified) [6-1] page 01 of 02)

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